

**IN THE CLAIMS**

Claim 1 (currently amended): A probe frame assembly of an inspection apparatus for a liquid crystal display device, comprising:

at least two separate probe frame bodies provided above an upper surface of a chuck for simultaneously applying test pattern signals to shorting bars provided on ~~one~~ or more a plurality of liquid crystal display panels disposed on a glass substrate.

Claim 2 (original): The probe frame assembly according to claim 1, wherein each of the probe frame bodies includes:

probe frame contact pins being in contact with the shorting bars;

a pogo pin set for insertion into a pogo pin contact provided on the chuck for delivering the test pattern signals to the probe frame contact pins;

a vacuum pad that is drawn to the chuck when a vacuum is applied; and

an alignment-adjusting member for positioning the pogo pin set to align with the pogo pin contact.

Claim 3 (currently amended): A method of testing a liquid crystal display panel using the probe assembly according to claim 1, the method including:

simultaneously applying the test pattern signals to the shorting bars of the ~~one or more~~ plurality of liquid crystal display panels.

Claim 4 (currently amended): An inspection apparatus for a liquid crystal display device, comprising:

a chuck loaded with a glass substrate having a plurality of ~~one or more~~ liquid crystal display panels;

a multiplex board attached to one side of the chuck for frequency-dividing test pattern signals; and

a probe frame assembly including at least two separate probe frame bodies being provided above an upper surface of the chuck for simultaneously applying the test pattern signals to a shorting bar provided on each of the plurality of ~~one or more~~ liquid crystal display panels.

Claim 5 (currently amended): The inspection apparatus according to claim 4, wherein the probe frame assembly has at least three separate probe frame bodies that simultaneously apply test patterns to the plurality of ~~at least six~~ liquid crystal display panels.

Claim 6 (original): The inspection apparatus according to claim 4, wherein the chuck includes a pogo pin contact including a plurality of contact holes.

Claim 7 (original): The inspection apparatus according to claim 6, further comprising: a cable and a connector for electrically connecting the pogo pin contact to the multiplex board.

Claim 8 (original): The inspection apparatus according to claim 7, wherein the cable and the connector are provided on a side of the chuck.

Claim 9 (original): The inspection apparatus according to claim 4, wherein each of the probe frame bodies includes:

probe frame contact pins in contact with the shorting bars;

a pogo pin set capable of being inserted into a pogo pin contact provided on the chuck for delivering test pattern signals to the probe frame contact pins;

a vacuum pad that is drawn to the chuck when a vacuum is applied; and

an alignment-adjusting member for positioning the pogo pin set to align with a pogo pin contact.

Claim 10 (currently amended): A method of testing a liquid crystal display panel using the probe assembly according to claim 4, the method including:

simultaneously applying the test pattern signals to the shorting bars of the plurality of ~~one or more~~ liquid crystal display panels.

Claim 11 (currently amended): An inspection apparatus for a liquid crystal display device, comprising:

a chuck loaded with a glass substrate having a plurality of ~~one or more~~ liquid crystal display panels;

a multiplex board attached to a side of the chuck to frequency-divide test pattern signals;

a probe frame assembly including at least two separate probe frame bodies being provided above an upper surface of the chuck for simultaneously applying the test pattern signals to a shorting bar provided on each one of the ~~one or more~~ plurality of liquid crystal display panels;

an electro-optical modulator for irradiating a light onto the plurality of ~~one or more~~ liquid crystal display panels; and

a base member for supporting the chuck, the probe frame assembly and the electro-optical modulator.

Claim 12 (currently amended): The inspection apparatus according to claim 11, wherein the probe frame assembly has at least three separate probe frame bodies that simultaneously apply test patterns to the plurality of ~~at least six~~ liquid crystal display panels.

Claim 13 (original): The inspection apparatus according to claim 11, wherein the chuck includes a pogo pin contact each having holes.

Claim 14 (original): The inspection apparatus according to claim 13, further comprising: a cable and a connector for electrically connecting the pogo pin contact to the multiplex board.

Claim 15 (original): The inspection apparatus according to claim 14, wherein the cable and the connector are provided at a side of the chuck.

Claim 16 (original): The inspection apparatus according to claim 11, wherein each of the probe frame bodies includes:

probe frame contact pins being in contact with a shorting bar;

a pogo pin set capable of being inserted into a pogo pin contact provided on the chuck for delivering test pattern signals to the probe frame contact pins;

a vacuum pad that is drawn to the chuck when a vacuum is applied; and

an alignment-adjusting member for positioning the pogo pin set to align with the pogo pin contact.

Claim 17 (currently amended): A method of testing a liquid crystal display panel using the probe assembly according to claim 11, the method including:

simultaneously applying the test pattern signals to the shorting bars of the

plurality of ~~one or more~~ liquid crystal display panels.

Claim 18 (currently amended): A method of testing a liquid crystal display panel using a probe frame assembly, the method including:

- loading a glass substrate patterned with a plurality of ~~one or more~~ LCD panels onto a chuck;
- lowering two or more probe frame bodies on the chuck; and
- simultaneously applying test pattern signals to all of the ~~one or more~~ LCD panels.

Claim 19 (original): The method of testing a liquid crystal display panel using a probe frame assembly according to claim 18, wherein each of the probe frame bodies includes:

- probe frame contact pins being in contact with a shorting bar;
- a pogo pin set capable of being inserted into a pogo pin contact provided on the chuck for delivering test pattern signals to the probe frame contact pins;
- a vacuum pad that is drawn to the chuck when a vacuum is applied; and
- an alignment-adjusting member for positioning the pogo pin set to align with the pogo pin contact.